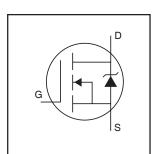
# International Rectifier

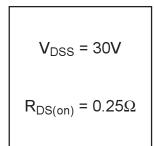
- Generation V Technology
- Ultra Low On-Resistance
- N-Channel MOSFET
- SOT-23 Footprint
- Low Profile (<1.1mm)
- Available in Tape and Reel
- Fast Switching
- Lead-Free

#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

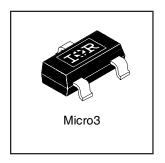
A customized leadframe has been incorporated into the standard SOT-23 package to produce a HEXFET Power MOSFET with the industry's smallest footprint. This package, dubbed the Micro3, is ideal for applications where printed circuit board space is at a premium. The low profile (<1.1mm) of the Micro3 allows it to fit easily into extremely thin application environments such as portable electronics and PCMCIA cards.





IRLML2803PbF

HEXFET® Power MOSFET



### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	1.2	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	0.93	А
I <sub>DM</sub>	Pulsed Drain Current ①	7.3	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation	540	mW
	Linear Derating Factor	4.3	mW/°C
$V_{GS}$	Gate-to-Source Voltage	±20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy®	3.9	mJ
dv/dt	Peak diode Recovery dv/dt <sup>②</sup>	5.0	V/ns
$T_{J}, T_{STG}$	Junction and Storage Temperature Range	-55 to + 150	°C

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ®		230	°C/W

### IRLML2803PbF

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TOR Rectifier

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.029		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Б	Static Drain to Source On Resistance			0.25		V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.91A ③
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.40	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.46A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
<b>9</b> fs	Forward Transconductance	0.87			S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.46A
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
יטכט	Brain to obtaine Educage Garrent			25	μΑ	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			-100	nA	$V_{GS} = -20V$
1655	Gate-to-Source Reverse Leakage			100	ПА	V <sub>GS</sub> = 20V
Qg	Total Gate Charge		3.3	5.0		$I_D = 0.91A$
Q <sub>gs</sub>	Gate-to-Source Charge		0.48	0.72	nC	V <sub>DS</sub> = 24V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		1.1	1.7		V <sub>GS</sub> = 10V, See Fig. 6 and 9 ③
t <sub>d(on)</sub>	Turn-On Delay Time		3.9			V <sub>DD</sub> = 15V
t <sub>r</sub>	Rise Time		4.0		ne	$I_D = 0.91A$
t <sub>d(off)</sub>	Turn-Off Delay Time		9.0		ns	$R_G = 6.2\Omega$
t <sub>f</sub>	Fall Time		1.7			$R_D$ = 16 $\Omega$ , See Fig. 10 $\Im$
C <sub>iss</sub>	Input Capacitance		85			V <sub>GS</sub> = 0V
Coss	Output Capacitance		34		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		15			f = 1.0MHz, See Fig. 5

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			0.54		MOSFET symbol
	(Body Diode)			0.54	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			7.0		integral reverse
	(Body Diode) ①			7.3		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25$ °C, $I_S = 0.91$ A, $V_{GS} = 0$ V ③
t <sub>rr</sub>	Reverse Recovery Time		26	40	ns	$T_J = 25^{\circ}C, I_F = 0.91A$
Q <sub>rr</sub>	Reverse RecoveryCharge		22	32	nC	di/dt = 100A/µs ③

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $@~I_{SD} \leq 0.91 A,~di/dt \leq 120 A/\mu s,~V_{DD} \leq V_{(BR)DSS},~T_{J} \leq 150 ^{\circ} C$

- $\ \ \,$  Limited by  $T_{Jmax},$  starting  $T_{J}$  = 25°C, L = 9.4mH,  $R_{G}$  = 25 $\Omega,$   $I_{AS}$  = 0.9A.

# International TOR Rectifier

### IRLML2803PbF

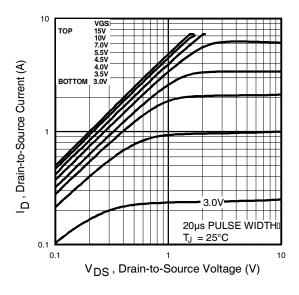


Fig 1. Typical Output Characteristics

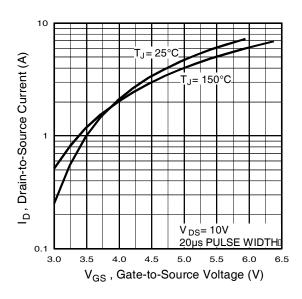


Fig 3. Typical Transfer Characteristics

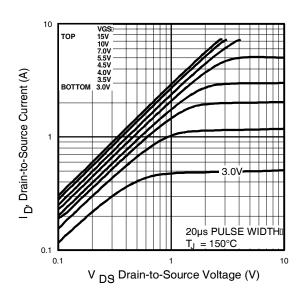
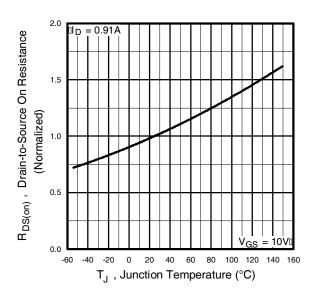
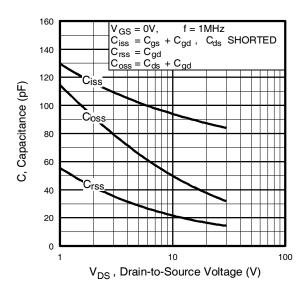


Fig 2. Typical Output Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

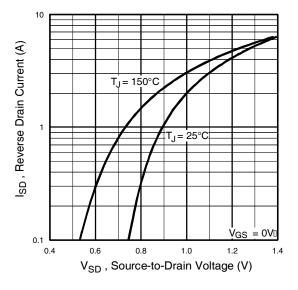
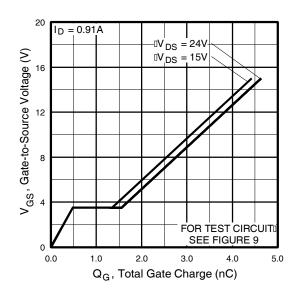


Fig 7. Typical Source-Drain Diode Forward Voltage www.irf.com



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

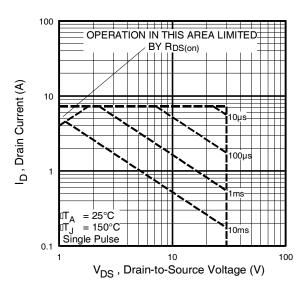
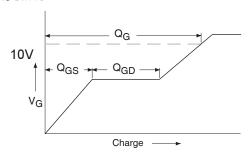


Fig 8. Maximum Safe Operating Area

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# International TOR Rectifier

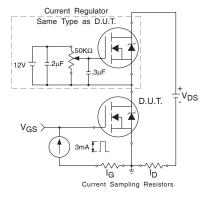
### IRLML2803PbF



 $V_{DS} \longrightarrow V_{DS}$   $V_{GS} \longrightarrow D.U.T.$   $R_{G} \longrightarrow V_{DD}$   $Pulse Width \leq 1 \ \mu s$   $Duty \ Factor \leq 0.1 \ \%$ 

Fig 9a. Basic Gate Charge Waveform

Fig 10a. Switching Time Test Circuit



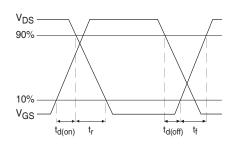


Fig 9b. Gate Charge Test Circuit

Fig 10b. Switching Time Waveforms

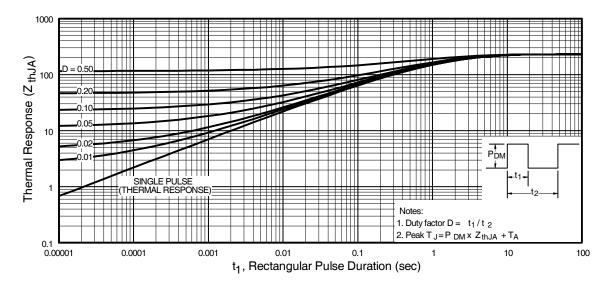


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

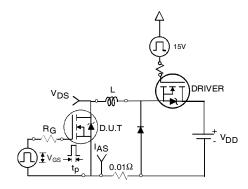


Fig 12a. Unclamped Inductive Test Circuit

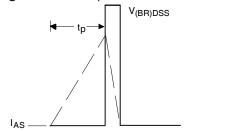
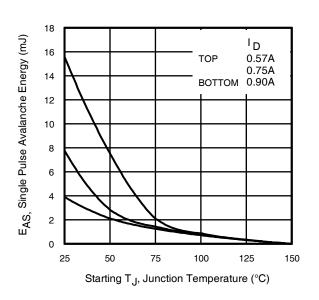


Fig 12b. Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

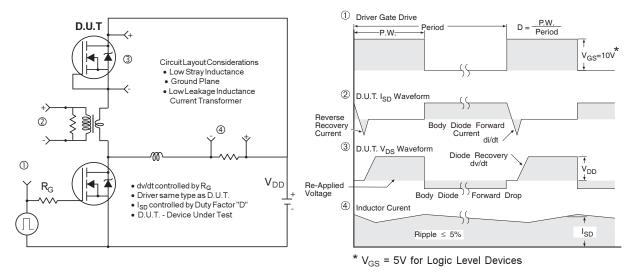


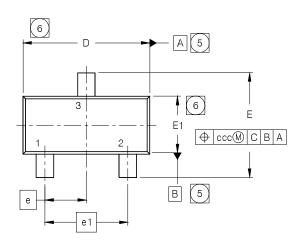
Fig 13. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

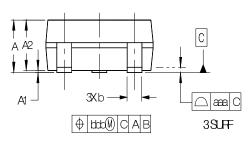
# International TOR Rectifier

### IRLML2803PbF

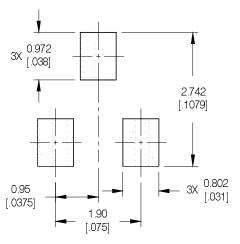
### Package Outline

Dimensions are shown in milimeters (inches)

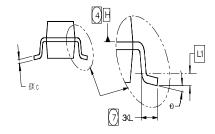




#### RECOMMENDED FOOTPRINT



S			1010110			
S Y M	DIMENSIONS					
B O L	MILLIM	IETERS	INCHES			
L	MIN	MAX	MIN	MAX		
Α	0.89	1.12	.036	044		
A1	0.01	0.10	.0004	.0039		
A2	0.88	1.02	.035	.040		
b	0.30	0.50	.0119	.0196		
С	0.08	0.20	.0032	.0078		
D	2.80	3.04	.111	119		
Е	2.10	2.64	.083	.103		
E1	1.20	1.40	.048	.055		
е	0.95 BSC		.0375 BSC			
e1	1.90	BSC	.075 BSC			
L	0.40	0.60	.0158	.0236		
L1	0.25 BSC		.0118 BSC			
Θ	0°	8°	0°	8°		
aaa	0.10		.004			
bbb	0.20		.008			
ССС	0.	15	.006			



#### NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS AND INCHES.
- 3. CONTROLLING DIMENSION: MILLIMETER.
- 4 DATUM PLANE H IS LOCATED AT THE MOLD PARTING LINE.
- $\boxed{5}$  DATUM A AND B TO BE DETERMINED AT DATUM PLANE H.
- 6) DIMENSIONS D AND E1 ARE MEASURED AT DATUM PLANE H.
- DIMENSION LIS THE LEAD LENGTH FOR SOLDERING TO A SUBSTRATE.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-236AB.

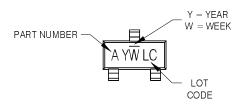
### IRLML2803PbF

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### Micro3 (SOT-23/TO-236AB) Part Marking Information





#### PARTNUMBER CODE REFERENCE:

A = IRLML2402

B = IRLML2803

C = IRLML6302

D = IRLML5103

E = IRLML6402

F = IRLML6401

G = IRLML2502

H = IRLML5203

Note: A line above the work week (as shown here) indicates Lead - Free.

YEAR	Υ	WORK WEEK	W
2001	1	01	A
2002	2	02	В
2003	3	03	С
2004	4	04	D
2005	5		
2006	6		
2007	7		
2008	8	1	1
2009	9	<b>y</b>	7
2010	0	24	Χ
		25	Υ
		26	Z

W = (27-52) IF PRECEDED BY A LETTER

YEAR	Υ	WORK WEEK	W
2001 2002	A B	27 28	A B
2003 2004 2005	C D E	29 30	C D
2006 2007	F G		
2008 2009	H J	<b>†</b>	Ų.
2010	K	50 51 52	X Y Z

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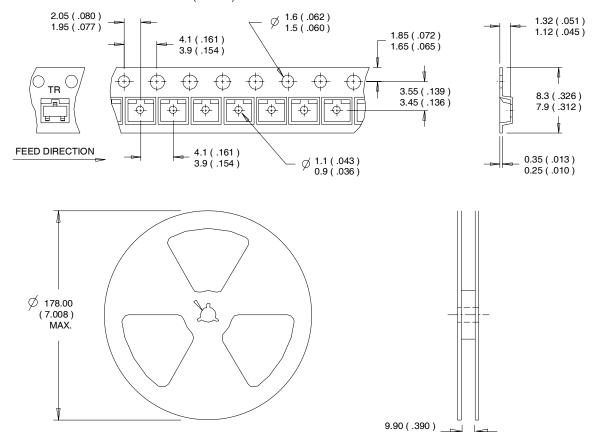
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### IRLML2803PbF

### Tape & Reel Information

#### SOT-23

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice.

8.40 (.331)



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